

Specification	AXPLO2600	Rev.: 1	Date: 2018-10-29
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Oscillator type: UHF Ultra-Low Noise Phase-Locked OCXO (PLOCXO)

Parameter	min.	typ.	max.	Unit	Condition
Reference frequency (input) f_{REF}	10		150	MHz	
Output frequency f_{OUT}	500		3000	MHz	Multiplication (Note 2)
Frequency stability (free running)					
frequency tolerance			±500	ppb	
vs. operating temperature range			±100	ppb	steady state
vs. supply voltage variation (pushing)			±10	ppb	$V_S \pm 5\%$
vs. load change (pulling)			±10	ppb	$R_L \pm 5\%$
Long term (aging) per day			±2	ppb	after 30 days operation
Long term (aging) per year			±200	ppb	after 30 days operation
Reference input (Note 3)					
Frequency accuracy			±500	ppb	
Signal waveform	Sine wave				
Input level	+3		+13	dBm	
Input impedance	50			Ω	
RF output					
Signal waveform	Sine wave				
Load R_L	50			Ω	±5%
Output level	+11	+13	+15	dBm	
Harmonics			-30	dBc	
Sub-harmonics		-50	-40	dBc	
PLL Products			-60	dBc	
Spurious			-80	dBc	
Phase noise @ 1000 MHz (Note 4, 5)		-115	-110	dBc/Hz	@ 100 Hz
		-140	-135	dBc/Hz	@ 1 kHz
		-150	-145	dBc/Hz	@ 10 kHz
		-155	-150	dBc/Hz	@ 100 kHz
		-160	-150	dBc/Hz	@ ≥1 MHz
Lock detect (LD) output		0	1.0	V	Out of lock
	2.3	3.3		V	Locked
Supply voltage V_S (Note 6)	11.4	12.0	12.6	V	
Current consumption (warm-up)			600	mA	
Current consumption (steady state)			300	mA	@ +25°C
Operating temperature range	-10		+60	°C	
Enclosure (see drawing) (LxWxH)	60x60x30 max.			mm	
DC connectors	Feedthrough Micro-D				Option 1 = "FT" Option 1 = "MD"
Weight			200	g	
Packing	Palette				

Notes:

1. Terminology and test conditions are according to IEC60679-1 and MIL-PRF-55310, unless otherwise stated
2. Frequency multiplication factor N depends on output frequency f_{OUT}
3. Programmable version available on request
4. Phase noise for other frequencies please consult factory
5. Phase noise performance for <100 Hz in locked state depends on reference oscillator
6. For other supply voltage please consult factory

Absolute Maximum Ratings

Parameter	min.	max.	Unit	Condition
Supply Voltage V_s	-0.5	$V_s + 10\%$	V	V_s to GND
Reference Input Level	-	+15	dBm	
Storage Temperature	-55	+105	°C	

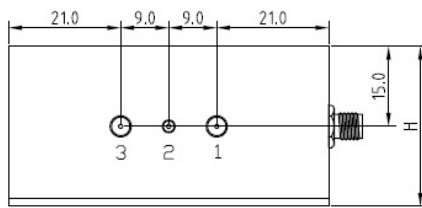
Ordering Code

Model	Option 1 [Package]	Input Frequency [MHz]	Output Frequency [MHz]	Revision
AXPLO2600	"FT" or "MD"	10	1000	Rev.1

Example: AXPLO2600-FT-10-1000_Rev.1 – 1000.000 MHz

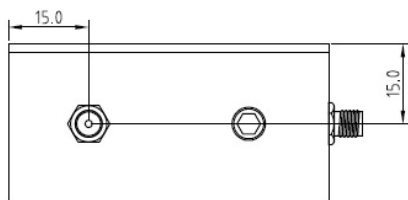
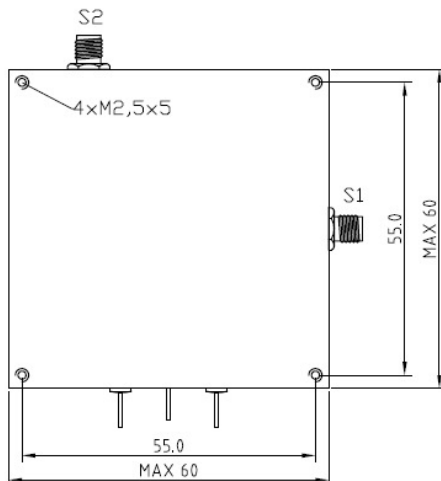
Enclosure drawing

Package Option FT "Feedthrough connectors"

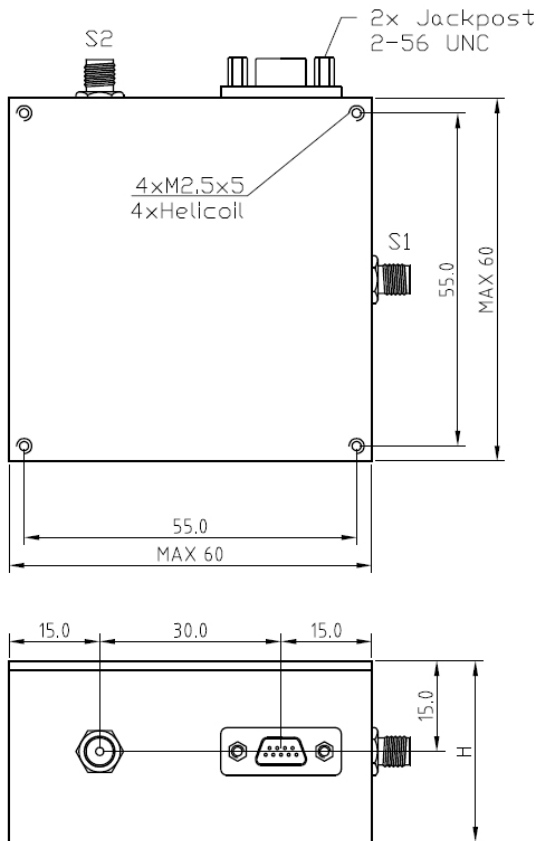


Pin connections:

Pin #	Symbol	Function
1	V_s	Supply Voltage
2	GND	Ground
3	LD	Lock Detect
SMA1	RF IN	RF Input FREF
SMA2	RF OUT	RF Output

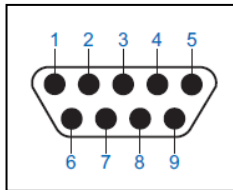


Package Option MD "Micro-D connector"



Pin connections:

Pin #	Symbol	Function
1	V _s	Supply Voltage
2	GND	Ground
3	LD	Lock Detect
SMA1	RF IN	RF Input FREF
SMA2	RF OUT	RF Output



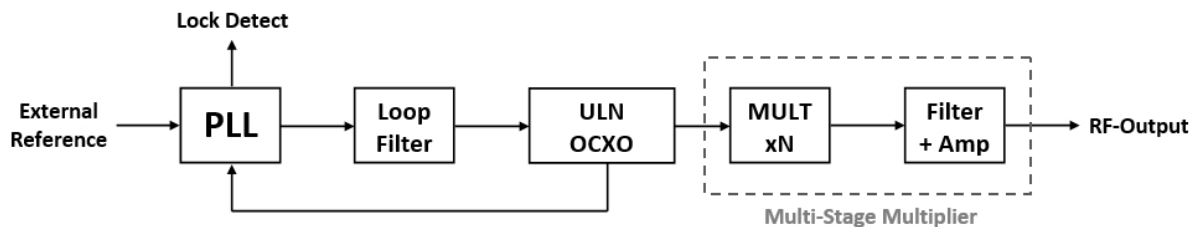
Front View Micro-D connector

Pin connections Micro-D connector:

Pin #	Symbol	Function
1	V _s	Supply voltage
2	V _s	Supply voltage
3	GND	Ground
4	GND	Ground
5	D.N.C.	Do Not Connect
6	LD	Lock Detect
7	D.N.C.	Do Not Connect
8	D.N.C.	Do Not Connect
9	D.N.C.	Do Not Connect

Micro-D Connector: M83513/03 with jack posts M83513/05-07 (2-56 UNC)

Block diagram



Handling and Testing

Parameter	Procedure		Source
Handling and Testing	Application Note AXAN-011		www.axtal.com
Processing	Application Note AXAN-012		www.axtal.com
Parameter	Procedure		Condition
Electrostatic discharge (ESD)			
THD devices	IEC60749-26	HBM	2000 V
SMD devices	IEC60749-27	MM	200 V
Washable	<input checked="" type="checkbox"/> Yes <input type="checkbox"/> No		
RoHS- Compliant	<input checked="" type="checkbox"/> Yes <input type="checkbox"/> No		

Environmental conditions

Test	IEC 60068 Part ...	IEC 60679-1 Clause	MIL-STD-202G Method	MIL-STD-810F Method	MIL-PRF-55310D Clause	Test conditions (IEC)
Sealing tests (if applicable)	2-17	5.6.2	112E		3.6.1.2	Gross leak: Test Qc, Fine leak: Test Qk
Solderability	2-20	5.6.3	208H		3.6.52	Test Ta Method 1
Resistance to soldering heat	2-58		210F		3.6.48	Test Td ₁ Method 2 Test Td ₂ Method 2
Shock*	2-27	5.6.8	213B	516.4	3.6.40	Test Ea, 3 x per axes 100g, 6 ms half-sine pulse
Vibration, sinusoidal*	2-6	5.6.7.1	201A 204D	516.4-4	3.6.38.1 3.6.38.2	Test Fc, 30 min per axes, 10 Hz - 55 Hz 0,75mm; 55 Hz - 2 kHz, 10g
Vibration, random*	2-64	5.6.7.3	214A	514.5	3.6.38.3 3.6.38.4	Test Fdb
Endurance tests - ageing - extended aging		5.7.1 5.7.2	108A		4.8.35	30 days @ 85°C, OCXO @25°C 1000h, 2000h, 8000h @85°C

Other environmental conditions on request

Data sheet is for information purposes only and may be subject to modifications or may be discontinued without notice.

Revision History

Rev.	Drawing	Date [dd.mm.yyyy]	Remarks	Author	Checked
1	D0	29.10.2018	First issue	HH	ME